IN THE CLAIMS

Please amend the claims as follows. This listing of claims replaces all prior versions and listings of claims in the application:

1. (Currently Amended) A method for monitoring ~~of~~ a manufacturing process of a plurality of physical objects, the method comprising the steps of <u>automatically, without human intervention</u>:

performing an analysis ~~by~~ using values of at least one process parameter of the manufacturing process of the plurality of physical objects;

determining that at least one physical object of the plurality of physical objects does not satisfy a prescribed selection criterion;

marking the at least one physical object in such a way that the at least one marked physical object must be sent for a special measurement; and

removing the at least one marked physical object from the manufacturing process.

2. (Previously Presented) The method of claim 1 wherein the physical object is a wafer.

3. (Previously Presented) The method of claim 1 wherein the analysis is a statistical analysis.

4. (Previously Presented) The method of claim 1 wherein the values of the at least one process parameter are measured when the plurality of physical objects is being manufactured.

5. (Previously Presented) The method of claim 1, further comprising:
sending the at least one marked physical object for a special measurement.

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6.   (Previously Presented) The method of claim 5 wherein the special measurement is a measurement for checking the quality of the at least one marked physical object.

7.   (Previously Presented) The method of claim 1, further comprising:
continuing the manufacturing process for any of the plurality of physical objects not marked as failing the prescribed selection criterion.

8.   (Previously Presented) The method of claim 1, wherein the selection criterion is a quality characteristic of the manufacturing process.

9.   (Previously Presented) The method of claim 1, wherein the selection criterion is not satisfied if a value of the at least one process parameter goes above or below a prescribed limit value.

10.   (Currently Amended) A device for monitoring a manufacturing process of a plurality of physical objects with a processor which is set up in such a way that the following method steps ~~can be~~ are carried out automatically, without human intervention:
performing an analysis using values of at least one process parameter of the manufacturing process of the plurality of physical objects;
marking at least one ~~of~~ physical object when, as a result of the analysis, the at least one physical object does not satisfy a prescribed selection criterion;
removing the at least one marked physical object from the manufacturing process; and
sending the at least one marked physical object for special treatments.

11.   (Currently Amended) A computer-readable storage medium, in which a program for monitoring a manufacturing process of a plurality of physical objects is stored, the program performing the following method steps automatically, without human intervention ~~when it is run by a processor~~:

performing analysis using values of at least one process parameter of the manufacturing process of the plurality of physical objects;

marking at least one ~~of~~ physical object when, as a result of the analysis, the at least one physical object does not satisfy a prescribed selection criterion;

removing the at least one marked physical object from the manufacturing process; and

sending the at least one marked physical object for special treatments.

12. (Currently Amended) A computer program element for monitoring ~~of~~ a manufacturing process of a plurality of physical objects, the computer program executing the following method steps <u>automatically, without human intervention</u> ~~when it is run by a processor~~:

performing an analysis using values of at least one process parameter of the manufacturing process of the plurality of physical objects;

marking at least one physical object when, as a result of the analysis, the at least one physical object does not satisfy a prescribed selection criterion;

removing the at least one marked physical object from the manufacturing process; and

sending the at least one marked physical object for special treatments.

13. (Previously Presented) The method of claim 1, further comprising:

preventing values associated with the at least one marked physical object from affecting an average product quality of the plurality of physical objects.

14. (Previously Presented) The device of claim 10, wherein the processor is further set up to carry out the set of:

preventing values associated with the at least one marked physical object from affecting an average product quality of the plurality of physical objects.

15. (Previously Presented) The computer-readable storage medium of claim 11, wherein the program further performs the step of:

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preventing values associated with the at least one marked physical object from affecting an average product quality of the plurality of physical objects.

16.   (Previously Presented) The Computer program element of claim 12, wherein the computer program further executes the step of:

preventing values associated with the at least one marked physical object from affecting an average product quality of the plurality of physical objects.